

<b>Notice of References Cited</b>	Application/Control No. 10/046,929	Applicant(s)/Patent Under Reexamination MULLEN, PATRICK W.
	Examiner Mark Tsidulko	Art Unit 2875

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0145860	10-2002	Lee, Hea-Chun	362/26
	B	US-6,424,396	07-2002	Kim et al.	349/130
	C	US-2002/0105793	08-2002	Oda et al.	362/31
	D	US-5,396,350	03-1995	Beeson et al.	349/62
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.